

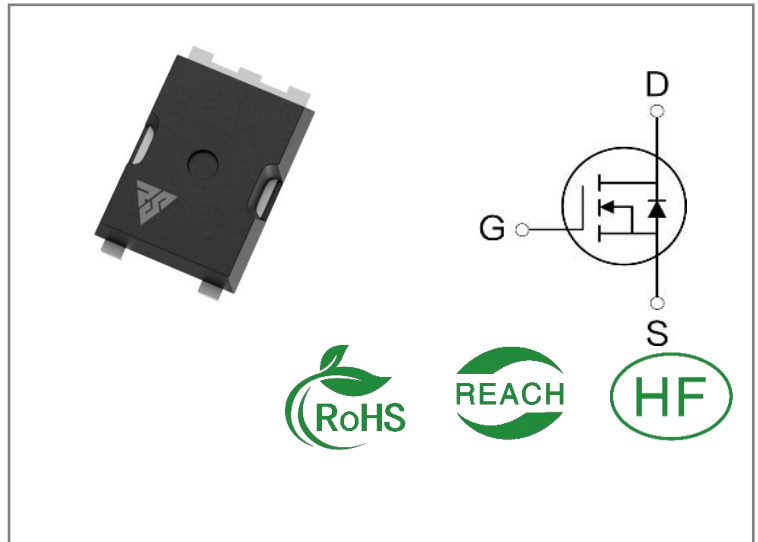
ID	$R_{DS(ON)}$ (Typ)	VDSS
20A	170mΩ	650V

Applications:

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- AC-DC Switching Power Supply

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



Ordering Information

Part Number	Package	Marking	Packing	Qty.
RS65R190BD	PTO-252	RS65R190BD	Tape&reel	3000 PCS

Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	RS65R190BD	Units
VDSS	Drain-to-Source Voltage	650	V
ID	Continuous Drain Current $T_C=25^\circ\text{C}$	20	A
ID	Continuous Drain Current $T_C=100^\circ\text{C}$	13	
IDM	Pulsed Drain Current (Note*1)	60	
PD	Power Dissipation	136	W
VGS	Gate- to- Source Voltage	± 30	V
EAS	Single Pulse Avalanche Energy $L=10\text{mH}, V_{DS}=50\text{V}, R_G=25\Omega, T_C=25^\circ\text{C}$	310	mJ
dv/dt	MOSFET dv/ dt ruggedness $V_{DS}=0\sim 400\text{V}$	50	V/ns
dv/dt	Reverse diode dv/dt $V_{DS}=0\sim 400\text{V}, T_j=25^\circ\text{C}, I_{SD}\leq I_D$	15	V/ns
TL TPKG	Maximum Temperature for Soldering	300	$^\circ\text{C}$
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	260	
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the " Absolute Maximum Ratings" Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS65R190BD	Units	Test Conditions
R θ JC	Junction-to-Case	0.92	°C / W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 °C
R θ JA	Junction-to- Ambient	80		1 cubic foot chamber,free air.

OFF Characteristics TJ= 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	650	--	--	V	VGS=0V ID=250μA
IDSS	Drain- to- Source Leakage Current	--	--	1	μA	VDS=650V VGS=0V
IGSS	Gate- to- Source Forward Leakage	--	--	100	nA	VGS=30V VDS=0V
	Gate- to- Source Reverse Leakage	--	--	-100		VGS=-30V VDS=0V

ON Characteristics TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On-Resistance(Note*2)	--	170	190	mΩ	VGS=10V ID=10A
VGS(TH)	Gate Threshold Voltage	3.0	4.0	5.0	V	VGS=VDS ID=250μA

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time	--	23	--	nS	VDS=325V ID=20A RG=25Ω
trise	Rise Time	--	35	--		
td(OFF)	Turn- OFF Delay Time	--	113	--		
tfall	Fall Time	--	28	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	1490	--	pF	VGS=0V VDS=50V f=1.0MHz
Coss	Output Capacitance	--	101	--		
Crss	Reverse Transfer Capacitance	--	2.3	--		
Qg	Total Gate Charge	--	36	--	nC	VDS=520V ID=20A VGS=10V
Qgs	Gate- to- Source Charge	--	7.2	--		
Qgd	Gate-to-Drain(" Miller") Charge	--	16	--		

Source- Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	20	A	Integral pn- diode in MOSFET
ISM	Maximum Pulsed Current	--	--	60	A	
VSD	Diode Forward Voltage	--	--	1.0	V	IS=20A VGS=0V
trr	Reverse Recovery Time	--	347	--	nS	VR=100V IS=20A di/dt=100A/μs
Qrr	Reverse Recovery Charge	--	5	--	μC	

Notes:

- * 1. Repetitive rating, pulse width limited by maximum junction temperature.
- * 2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 2%

Typical Feature Curve

Figure1. Output Characteristics

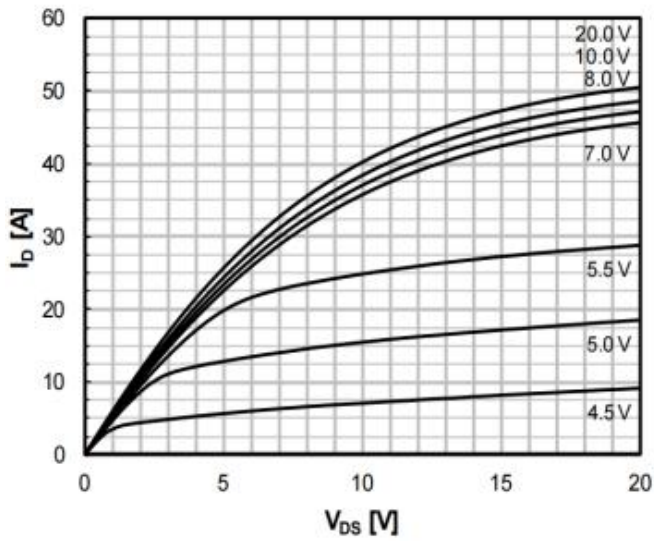


Figure2. Transfer Characteristics

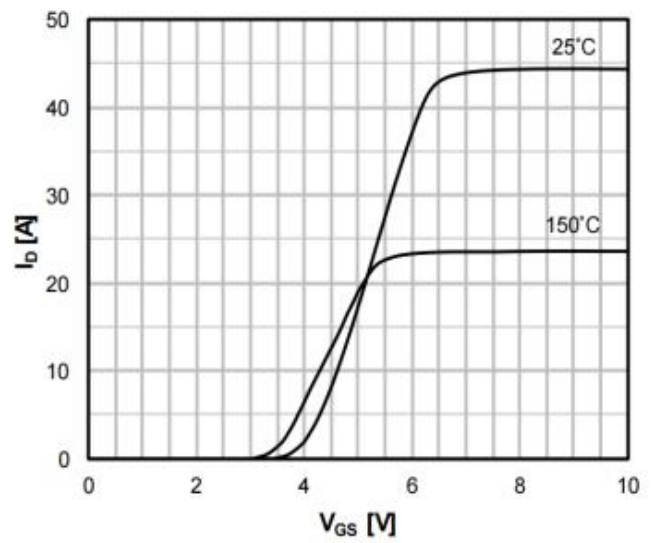


Figure 3. On-Resistance VS.Drain Current

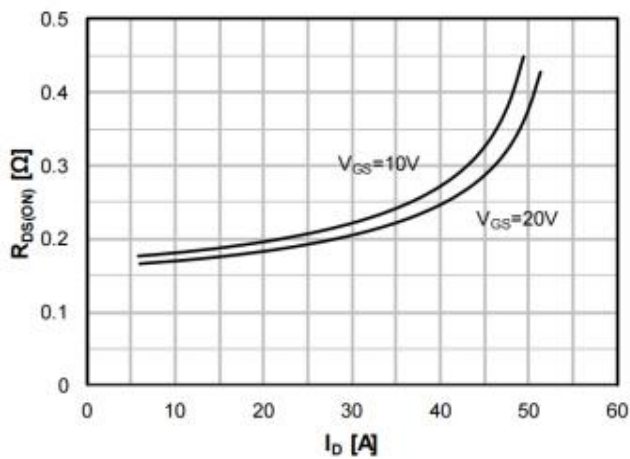


Figure 4. Capacitance

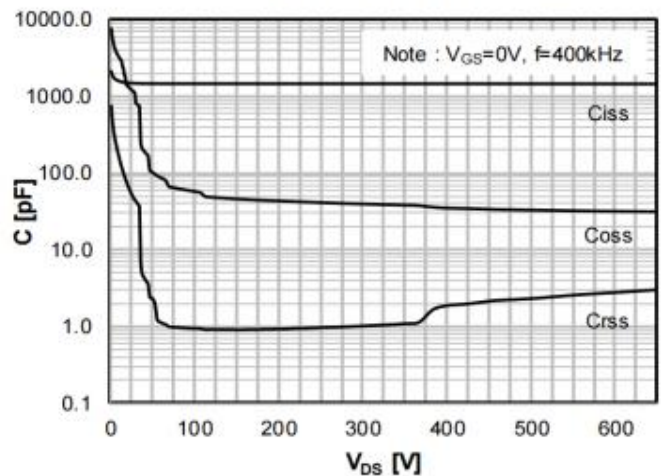


Figure 5. Gate Charge

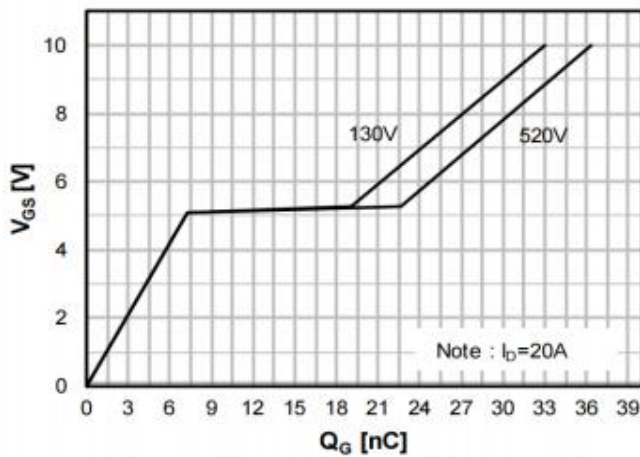


Figure 6. Body Diode Forward Voltage

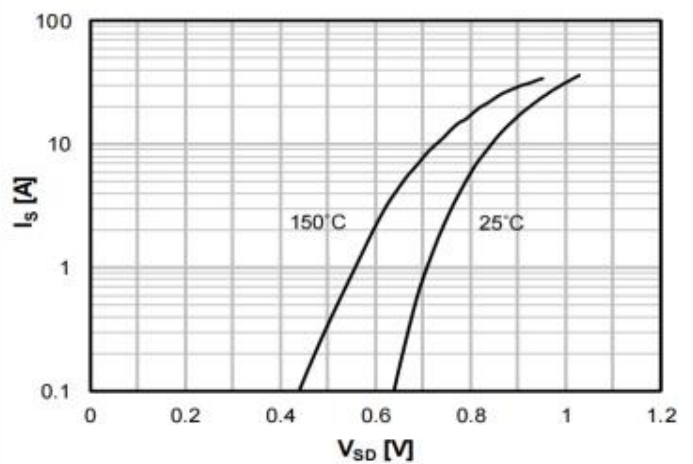


Figure 7. On-Resistance vs. Junction Temperature

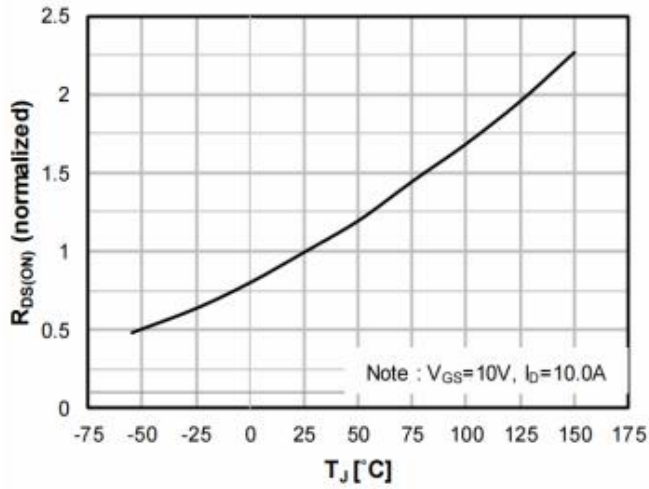


Figure 8. Breakdown Voltage vs. Junction Temperature

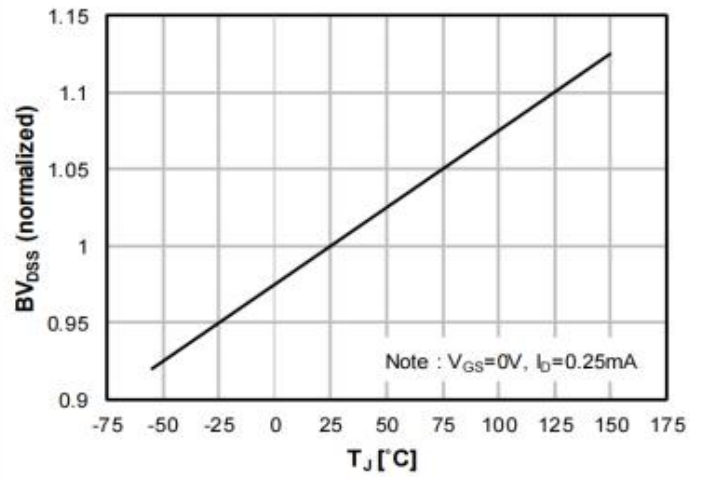


Figure 9. Safe operation area

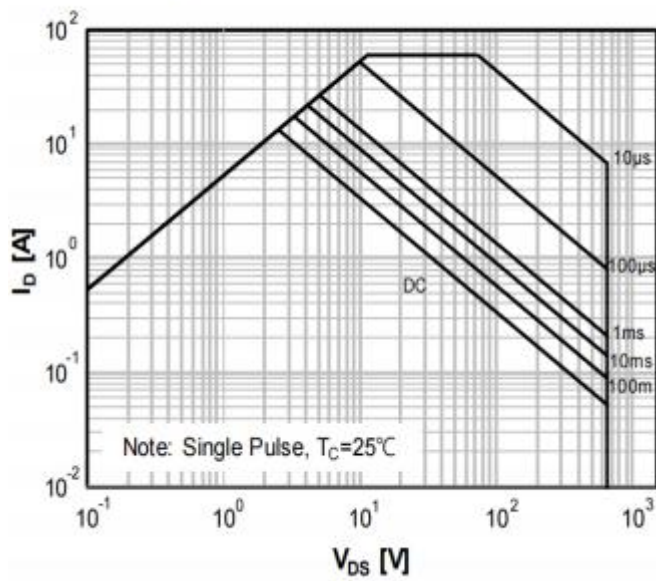
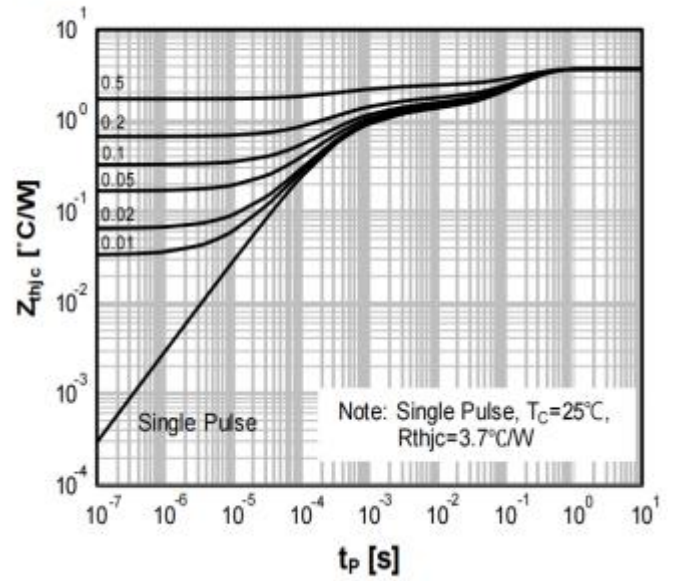


Figure 10. Transient Thermal Impedance



Test Circuits and Waveforms

Figure A: Gate Charge Test Circuit and Waveform

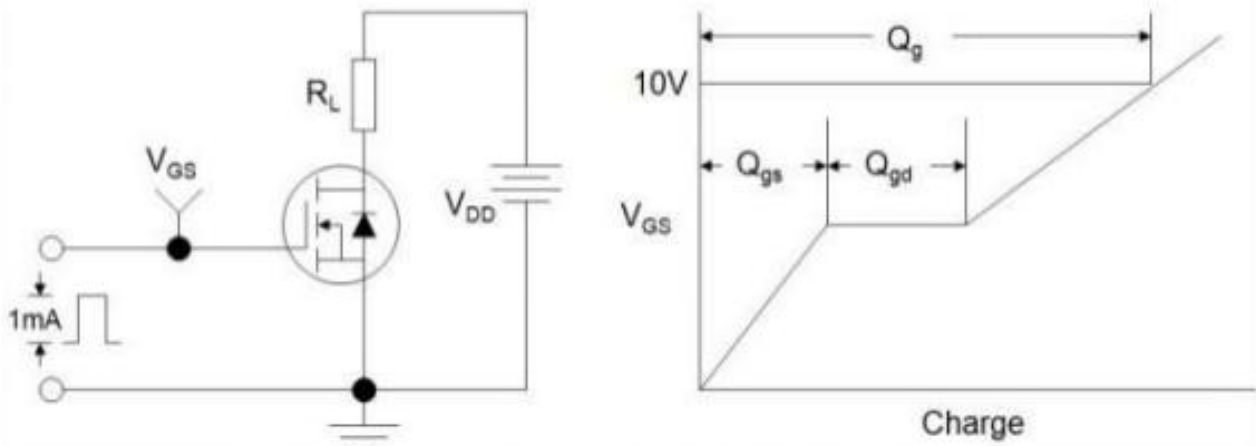


Figure B: Resistive Switching Test Circuit and Waveform

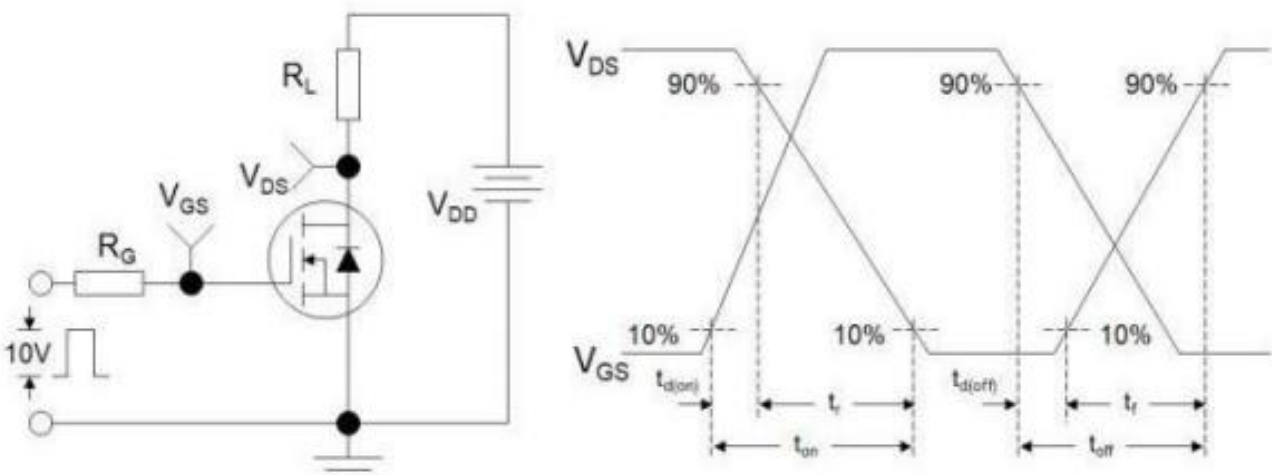
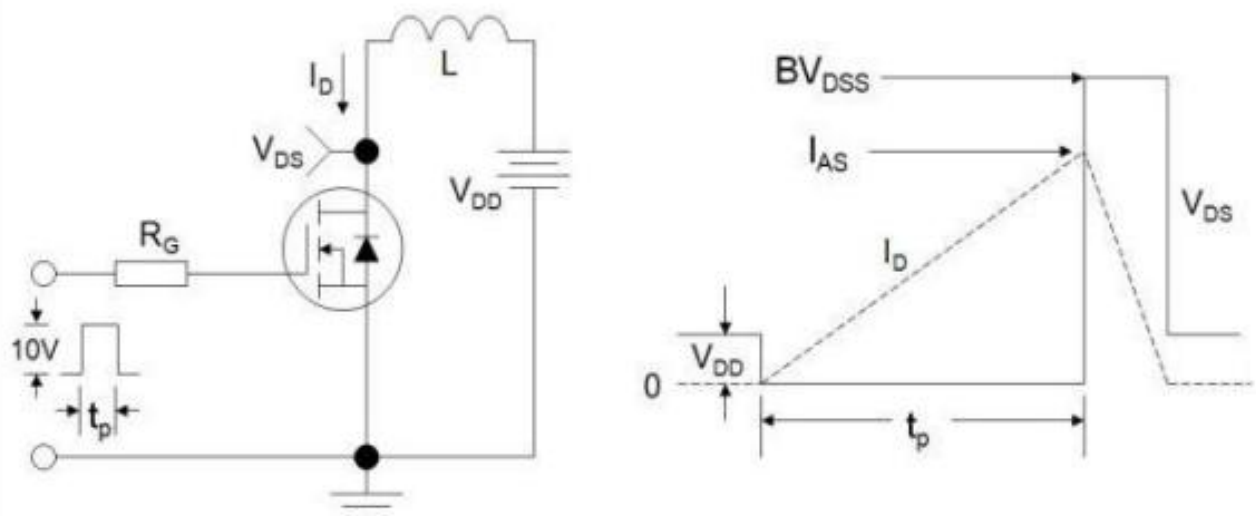
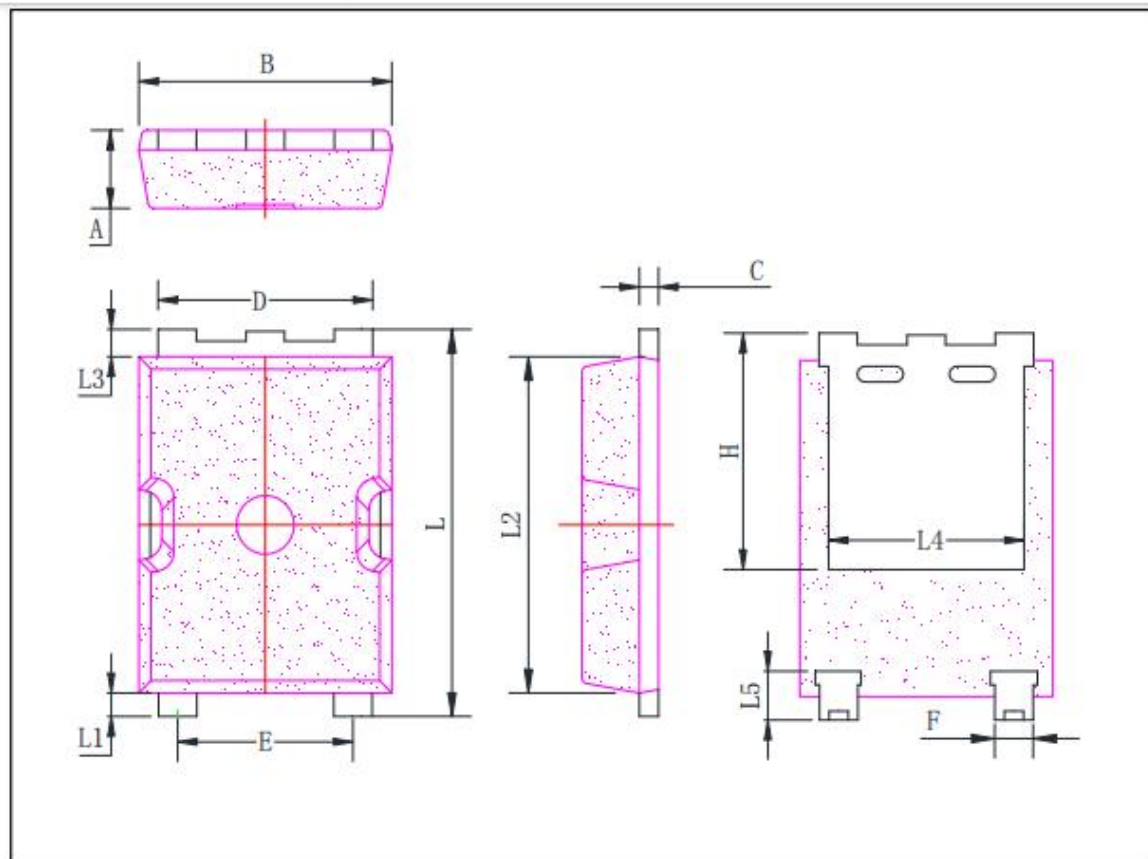


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package outline drawing(PTO-252 Unit: mm)



Symbol	Min	Typ	Max
A	1.90	2.00	2.10
B	6.50	6.60	6.70
C	0.45	0.50	0.60
D	5.50	5.60	5.70
E	4.50	4.60	4.70
F	0.90	1.00	1.05
H	5.95	6.15	6.25
L	9.80	9.90	10.0
L1	0.50	0.60	0.70
L2	8.50	8.60	8.70
L3	0.60	0.70	0.80
L4	4.65	4.80	4.90
L5	1.05	1.20	1.30

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